SHEET 1 OF 1

INFORMATION DISCLOSURE CITATION IN AN APPLICATION						ATTY. DOCKET NO. 57454-970		SERIAL NO. No. 10/644,750		
						APPLICANT Hideto HIDAKA				
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INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.								
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1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.